



ON Semiconductor®

## FDD2670

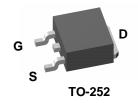
## 200V N-Channel PowerTrench<sup>®</sup> MOSFET

#### **General Description**

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

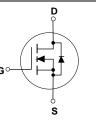
These MOSFET's feature faster switching and lower gate charge than other MOSFET's with comparable  $\mathsf{RDS}_{(\mathsf{ON})}$  specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.



#### Features

- 3.6 A, 200 V.  $R_{DS(ON)}$  = 130 m $\Omega$  @ V<sub>GS</sub> = 10 V
- Low gate charge
- Fas t switching speed
- + High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- High power and current handling capability



### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		200	V
V <sub>GSS</sub>	Gate-Source Voltage		±20	V
ID	Drain Current – Continuous	(Note 1)	3.6	A
	Drain Current – Pulsed		20	
PD	Maximum Power Dissipation @ T <sub>C</sub> = 25°C	(Note 1)	70	W
	(a) $T_A = 25^{\circ}C$ (	Note 1a)	3.2	
	(a) $T_A = 25^{\circ}C$ (	Note 1b)	1.3	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	3.2	V/ns
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature	Range	-55 to +150	°C

	Onaracteristics			
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	1.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

### Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDD2670	FDD2670	13"	16mm	2500 units

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Publication Order Number: FDD2670/D

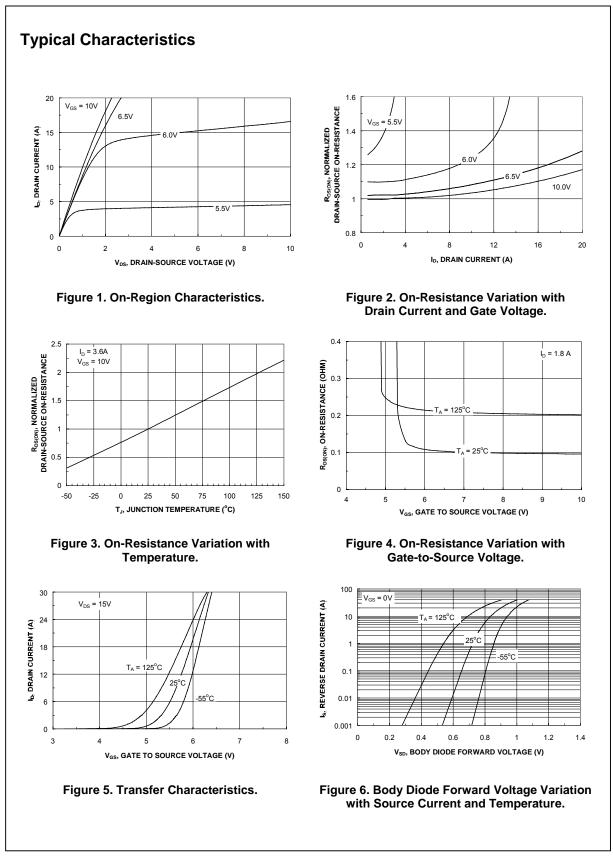
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W <sub>DSS</sub> 5           I <sub>AR</sub> I           Off Chara         I           BV <sub>DSS</sub> I           ΔBV <sub>DSS</sub> I           ΔT <sub>J</sub> G           I <sub>DSS</sub> 2           I <sub>GSSF</sub> G	Urce Avalanche Ratings (Note Single Pulse Drain-Source Avalanche Energy Maximum Drain-Source Avalanche Current Incteristics Drain–Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current	1) $V_{DD} = 100 \text{ V},  I_D = 3.6 \text{ A}$ $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$ $I_D = 250 \mu\text{A}, \text{ Referenced to } 25^{\circ}\text{C}$	200		375 3.6	mJ A
W <sub>DSS</sub> 5           I <sub>AR</sub> Γ           Off Chara         Γ           BV <sub>DSS</sub> Γ <u>ΔBV<sub>DSS</sub></u> Γ           ΔT <sub>J</sub> Γ           I <sub>DSS</sub> 2           I <sub>GSSF</sub> Γ	Single Pulse Drain-Source Avalanche Energy Maximum Drain-Source Avalanche Current Incteristics Drain–Source Breakdown Voltage Breakdown Voltage Temperature Coefficient	V <sub>DD</sub> = 100 V, I <sub>D</sub> = 3.6 A V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	200			
I <sub>AR</sub> Γ           Off Chara           BV <sub>DSS</sub> Γ           ΔBV <sub>DSS</sub> Γ           ΔTJ         Γ           I <sub>DSS</sub> 2           I <sub>GSSF</sub> Γ	Maximum Drain-Source Avalanche Current Drain–Source Breakdown Voltage Breakdown Voltage Temperature Coefficient		200		3.6	A
BV <sub>DSS</sub> Ι ΔBV <sub>DSS</sub> Ι ΔΤ <sub>J</sub> Ο Ι <sub>DSS</sub> 2 Ι <sub>GSSF</sub> Ο	Drain–Source Breakdown Voltage Breakdown Voltage Temperature Coefficient		200			
BV <sub>DSS</sub> Ι ΔBV <sub>DSS</sub> Ι ΔΤ <sub>J</sub> Ο Ι <sub>DSS</sub> 2 Ι <sub>GSSF</sub> Ο	Drain–Source Breakdown Voltage Breakdown Voltage Temperature Coefficient		200			
$\begin{array}{c c} \underline{\Delta B V_{DSS}} \\ \underline{\Delta T_J} \\ I_{DSS} \\ I_{GSSF} \end{array} \qquad \begin{array}{c} I \\ I $	Breakdown Voltage Temperature Coefficient					V
I <sub>DSS</sub> Z	Zero Gate Voltage Drain Current			214		mV/°C
	baile to the brain out off	V <sub>DS</sub> = 160 V, V <sub>GS</sub> = 0 V			1	μA
	Gate-Body Leakage, Forward	$V_{GS} = 20 V$ , $V_{DS} = 0 V$			100	NA
-0001	Gate–Body Leakage, Reverse	$V_{GS} = -20 V$ , $V_{DS} = 0 V$			-100	NA
On Chara	Cteristics (Note 2)	· ·				
	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	2	4	4.5	V
$\Delta V_{GS(th)}$ (	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25°C		-10		mV/°C
00(011)	Static Drain–Source On–Resistance	$V_{GS}$ = 10 V, $I_D$ = 3.6 A $V_{GS}$ = 10 V, $I_D$ = 3.6 A T <sub>J</sub> = 125°C		100 205	130 275	mΩ
I <sub>D(on)</sub>	On–State Drain Current	$V_{GS}$ = 10 V, $V_{DS}$ = 5 V	20			А
g <sub>FS</sub> I	Forward Transconductance	$V_{DS} = 5 V$ , $I_{D} = 3.6 A$		15		S
Dvnamic (	Characteristics					
	Input Capacitance	$V_{DS} = 100 V$ , $V_{GS} = 0 V$ ,		1228		PF
C <sub>oss</sub> (	Output Capacitance	f = 1.0 MHz		112		PF
C <sub>rss</sub> I	Reverse Transfer Capacitance			17		pF
Curitalia a	g Characteristics (Note 2)	•				
Switching						
	Turn–On Delay Time	Vpp = 100 V Ip = 1 A		13	23	ns
t <sub>d(on)</sub>		$V_{DD} = 100 V,$ $I_D = 1 A,$ $V_{GS} = 10 V,$ $R_{GEN} = 6 \Omega$		13 8	23 16	ns ns
t <sub>d(on)</sub> t <sub>r</sub>	Turn–On Delay Time	$V_{DD}$ = 100 V, $I_D$ = 1 A, V <sub>GS</sub> = 10 V, $R_{GEN}$ = 6 Ω				
t <sub>d(on)</sub> - t <sub>r</sub> - t <sub>d(off)</sub> -	Turn–On Delay Time Turn–On Rise Time			8	16	ns
t <sub>d(on)</sub> - t <sub>r</sub> - t <sub>d(off)</sub> - t <sub>f</sub> -	Turn–On Delay Time Turn–On Rise Time Turn–Off Delay Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		8 30	16 48	ns ns
t <sub>d(on)</sub> -           t <sub>r</sub> -           t <sub>d(off)</sub> -           t <sub>f</sub> -           Q <sub>g</sub> -	Turn–On Delay Time Turn–On Rise Time Turn–Off Delay Time Turn–Off Fall Time			8 30 25	16 48 40	ns ns ns
td(on)         -           tr         -           td(off)         -           tf         -           Qg         -           Qgs         -	Turn–On Delay Time Turn–On Rise Time Turn–Off Delay Time Turn–Off Fall Time Total Gate Charge	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$ $V_{DS}$ = 100 V, $I_D$ = 3.6 A,		8 30 25 27	16 48 40	ns ns ns nC
td(on)         -           tr         -           td(off)         -           tr         -           Qg         -           Qgs         -           Qgd         -	Turn–On Delay Time Turn–On Rise Time Turn–Off Delay Time Turn–Off Fall Time Total Gate Charge Gate–Source Charge Gate–Drain Charge	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$ $V_{DS} = 100 \text{ V}, \qquad I_D = 3.6 \text{ A},$ $V_{GS} = 10 \text{ V}$		8 30 25 27 7	16 48 40	ns ns nC nC
t <sub>d(on)</sub> - t <sub>r</sub> - t <sub>d(off)</sub> - t <sub>f</sub> - Q <sub>g</sub> - Q <sub>gs</sub> ( Q <sub>gd</sub> ( Drain–Sou	Turn–On Delay Time Turn–On Rise Time Turn–Off Delay Time Turn–Off Fall Time Total Gate Charge Gate–Source Charge	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$ $V_{DS} = 100 \text{ V}, \qquad I_D = 3.6 \text{ A},$ $V_{GS} = 10 \text{ V}$ and Maximum Ratings		8 30 25 27 7	16 48 40	ns ns nC nC

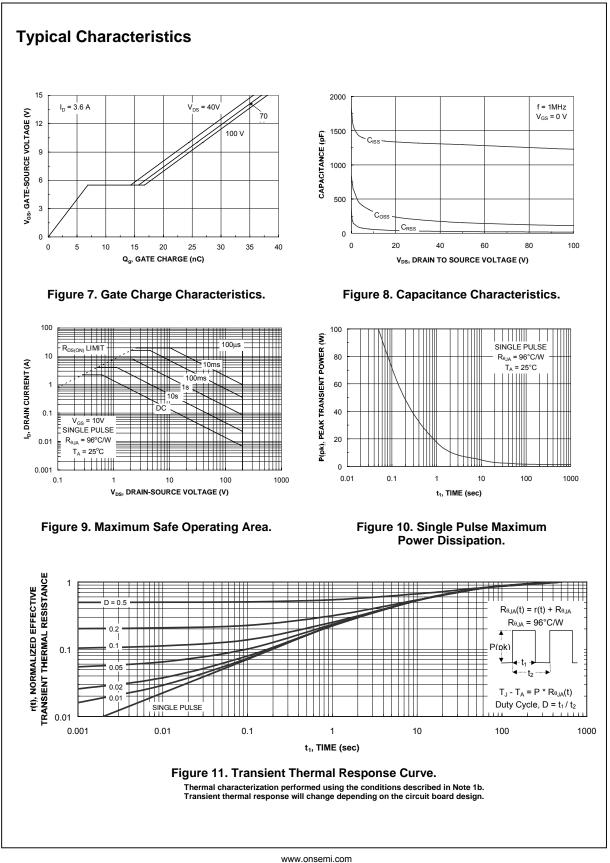
Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300 $\mu$ s, Duty Cycle < 2.0%

3.  $I_{SD} \leq$  3A, di/dt  $\leq$  100A/µs,  $V_{DD} \leq BV_{DSS},$  Starting  $T_{J}$  = 25°C



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